

TMD4N60 / TMI4N60 N-CHANNEL POWER MOSFET

General Description

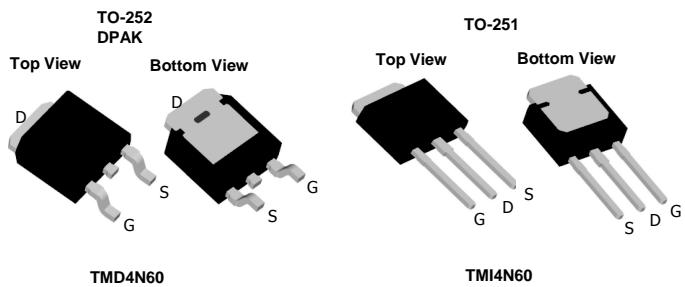
The TMD4N60 & TMI4N60 have been fabricated using an advanced high voltage MOSFET process that is designed to deliver high levels of performance and robustness in popular AC-DC applications. By providing low $R_{DS(on)}$, C_{iss} and C_{rss} along with guaranteed avalanche capability these parts can be adopted quickly into new and existing offline power supply designs.

Product Summary

V_{DS}	600V
I_D (at $V_{GS}=10V$)	4A
$R_{DS(ON)}$ (at $V_{GS}=10V$)	< 2.3Ω



100% UIS Tested!
100% R_g Tested!



Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	600	V
Gate-Source Voltage	V_{GS}	± 30	V
Continuous Drain Current ^B	I_D	4	A
$T_c=100^\circ C$		2.6	
Pulsed Drain Current ^C	I_{DM}	14	
Avalanche Current ^C	I_{AR}	2.8	A
Repetitive avalanche energy ^C	E_{AR}	118	mJ
Single pulsed avalanche energy ^H	E_{AS}	235	mJ
MOSFET dv/dt ruggedness	dv/dt	50	
Peak diode recovery dv/dt		5	V/ns
Power Dissipation ^B	P_D	104	W
$T_c=25^\circ C$		0.83	W/°C
Junction and Storage Temperature Range	T_J, T_{STG}	-50 to 150	°C
Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds	T_L	300	°C

Thermal Characteristics

Parameter	Symbol	Typical	Maximum	Units
Maximum Junction-to-Ambient ^{A,G}	$R_{\theta JA}$	43	55	°C/W
Maximum Case-to-sink ^A	$R_{\theta CS}$	-	0.5	°C/W
Maximum Junction-to-Case ^{D,F}	$R_{\theta JC}$	1	1.2	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}, T_J=25^\circ\text{C}$	600			V
$\text{BV}_{\text{DSS}}/\Delta T_J$	Zero Gate Voltage Drain Current	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$		0.67		$\text{V}/^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=600\text{V}, V_{GS}=0\text{V}$		1		μA
		$V_{DS}=480\text{V}, T_J=125^\circ\text{C}$		10		
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 30\text{V}$			± 100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=5\text{V}, I_D=250\mu\text{A}$	3.4	4.1	4.5	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=2\text{A}$		1.8	2.3	Ω
g_{FS}	Forward Transconductance	$V_{DS}=40\text{V}, I_D=2\text{A}$		6		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.76	1	V
I_S	Maximum Body-Diode Continuous Current			4		A
I_{SM}	Maximum Body-Diode Pulsed Current			14		A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=25\text{V}, f=1\text{MHz}$	420	528	640	pF
C_{oss}	Output Capacitance		35	53	70	pF
C_{rss}	Reverse Transfer Capacitance		2.5	4.8	7	pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	1.2	2.5	3.8	Ω
SWITCHING PARAMETERS						
Q_g	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=480\text{V}, I_D=4\text{A}$	9.5	12	14.5	nC
Q_{gs}	Gate Source Charge		2.8	3.6	4.5	nC
Q_{gd}	Gate Drain Charge		2.2	4.4	6.6	nC
$t_{D(on)}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=300\text{V}, I_D=4\text{A}, R_G=25\Omega$		17		ns
t_r	Turn-On Rise Time			26		ns
$t_{D(off)}$	Turn-Off Delay Time			34		ns
t_f	Turn-Off Fall Time			21		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=4\text{A}, dI/dt=100\text{A}/\mu\text{s}, V_{DS}=100\text{V}$	150	190	230	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=4\text{A}, dI/dt=100\text{A}/\mu\text{s}, V_{DS}=100\text{V}$	1.9	2.4	3	μC

- A. The value of $R_{\theta JA}$ is measured with the device in a still air environment with $T_A=25^\circ\text{C}$.
- B. The power dissipation P_d is based on $T_{J(\text{MAX})}=150^\circ\text{C}$ in a TO252 package, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.
- C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$.
- D. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to case $R_{\theta JC}$ and case to ambient.
- E. The static characteristics in Figures 1 to 6 are obtained using $<300\ \mu\text{s}$ pulses, duty cycle 0.5% max.
- F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$.
- G. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$.
- H. $L=60\text{mH}, I_{AS}=2.8\text{A}, V_{DD}=150\text{V}, R_G=10\Omega$, Starting $T_J=25^\circ\text{C}$

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

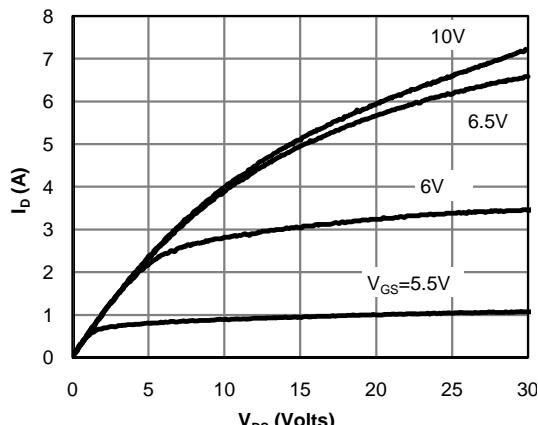


Fig 1: On-Region Characteristics

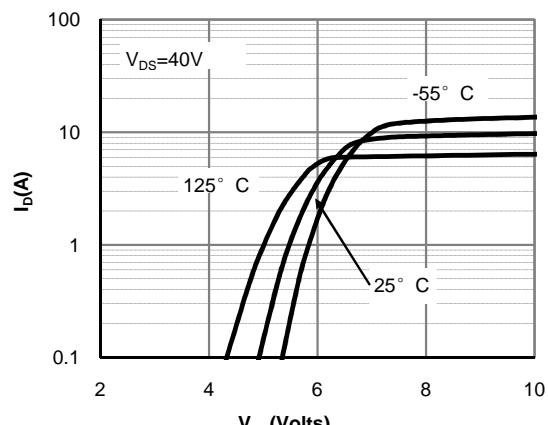


Figure 2: Transfer Characteristics

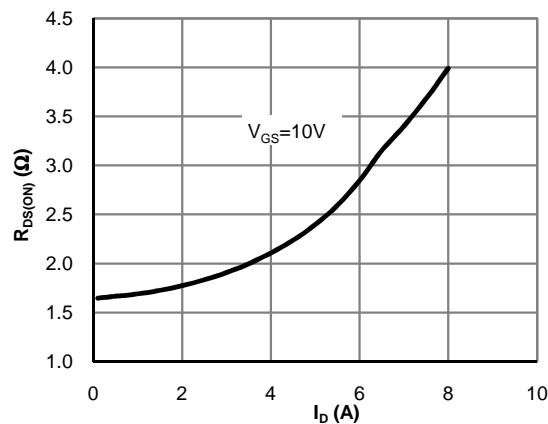


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

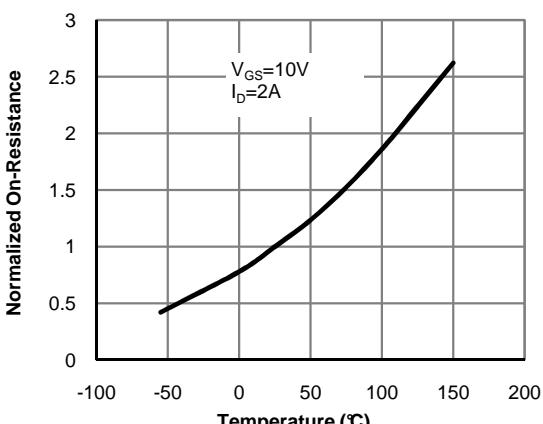


Figure 4: On-Resistance vs. Junction Temperature

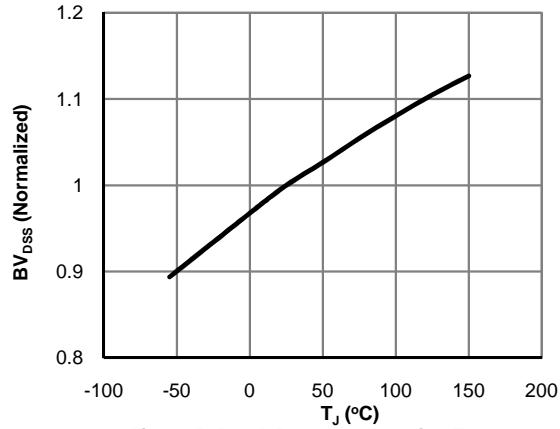


Figure 5: Break Down vs. Junction Temperature

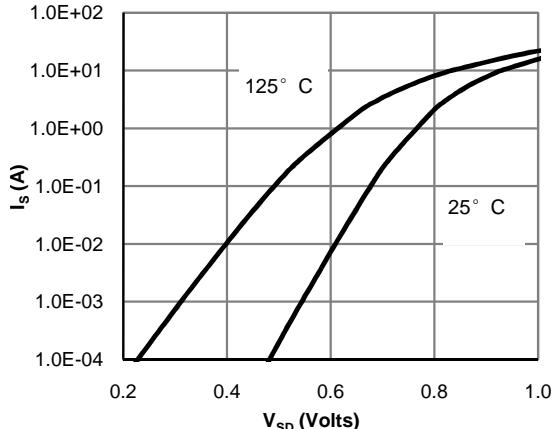


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

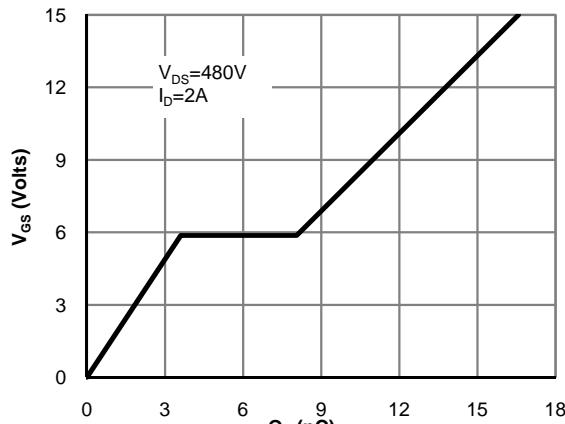


Figure 7: Gate-Charge Characteristics

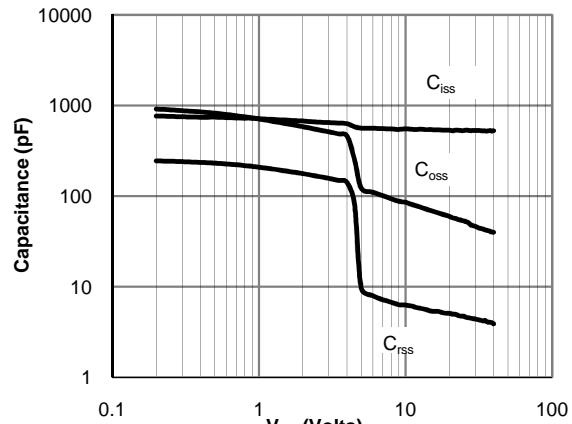


Figure 8: Capacitance Characteristics

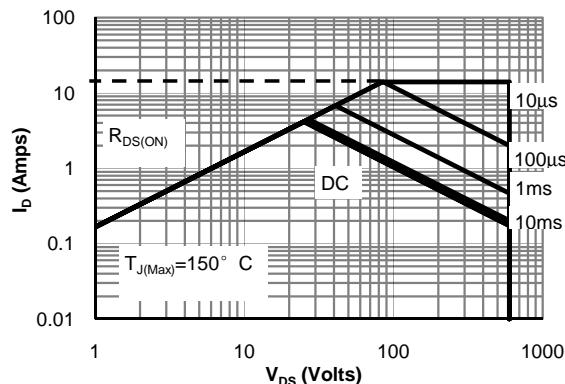


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

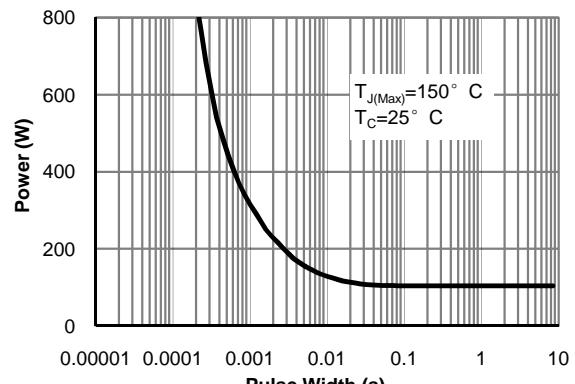


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

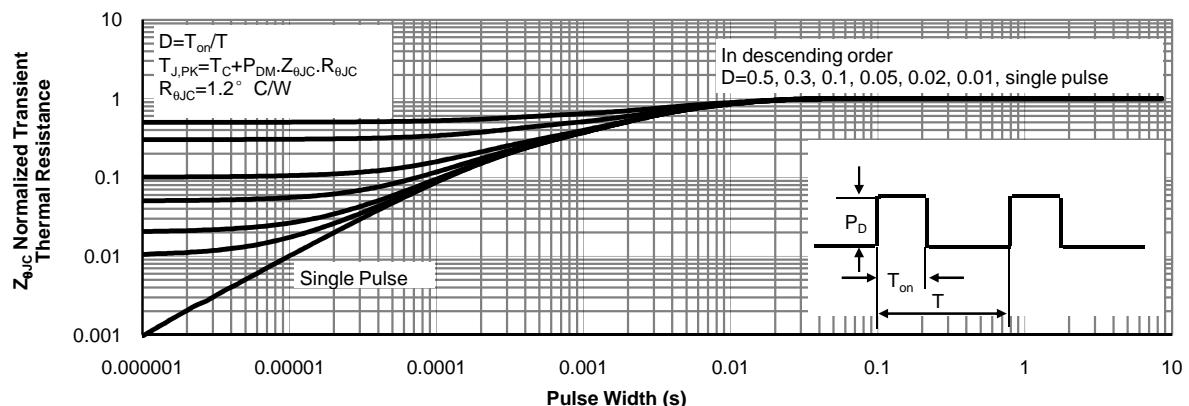


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

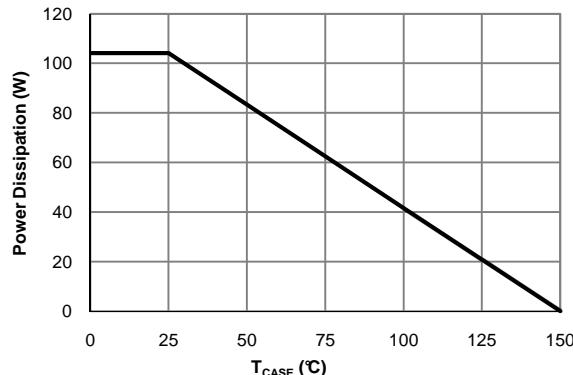


Figure 12: Power De-rating (Note B)

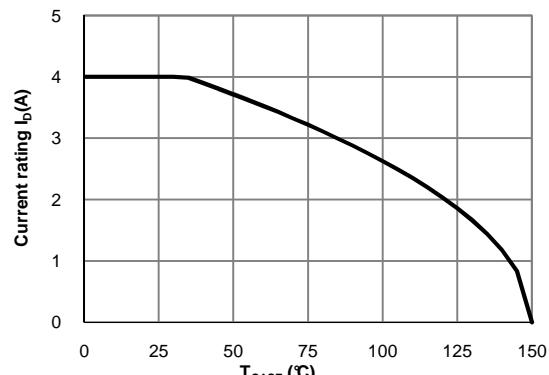


Figure 13: Current De-rating (Note B)

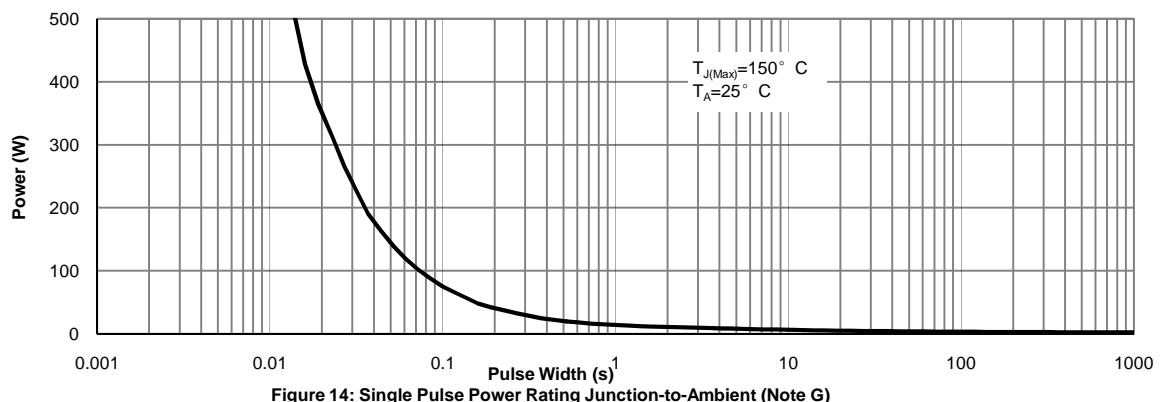


Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note G)

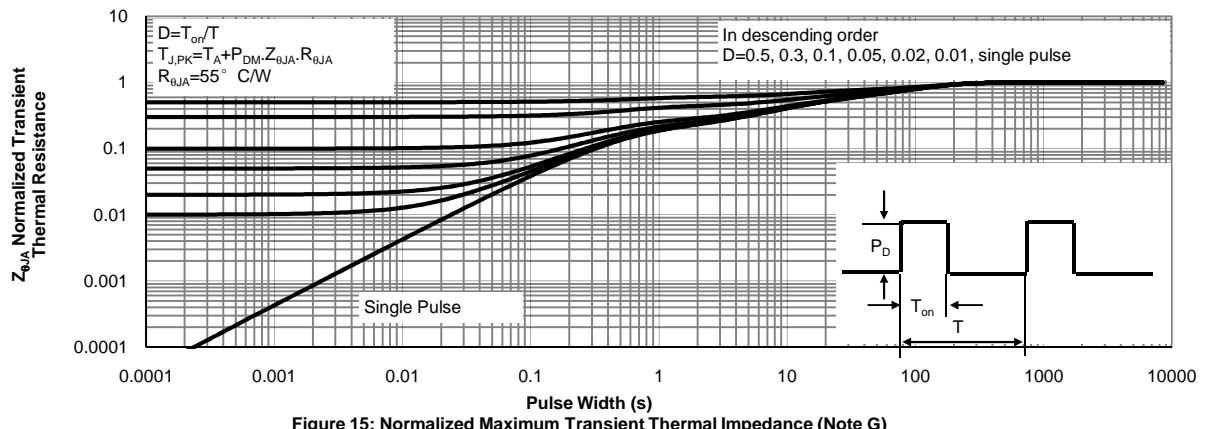
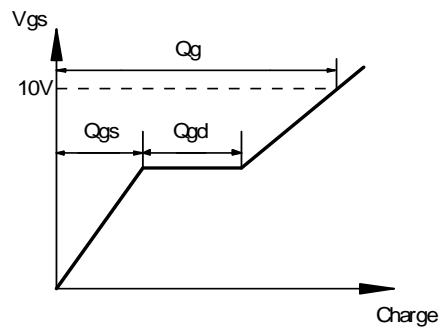
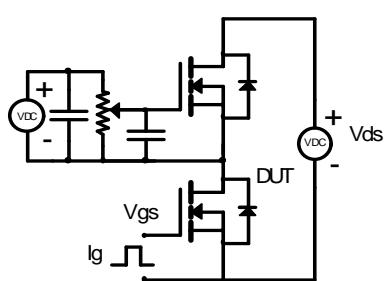
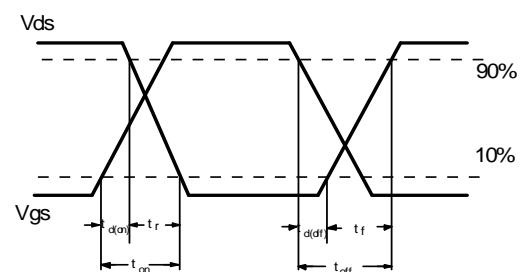
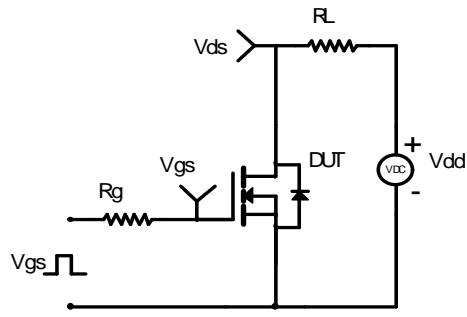


Figure 15: Normalized Maximum Transient Thermal Impedance (Note G)

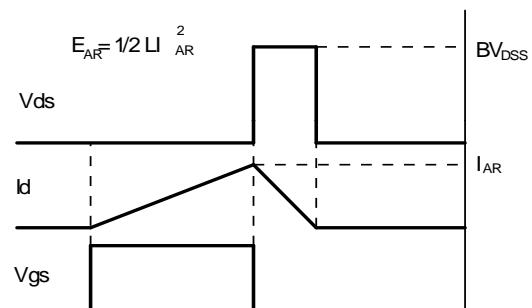
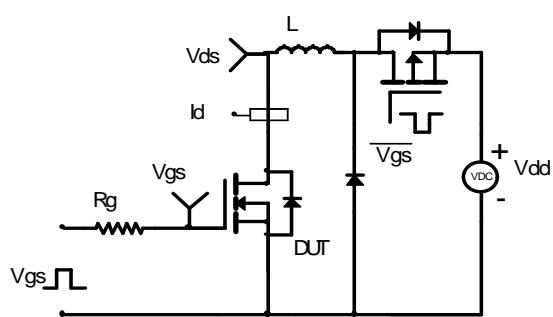
Gate Charge Test Circuit & Waveform



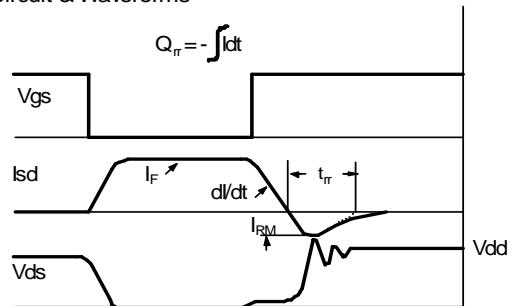
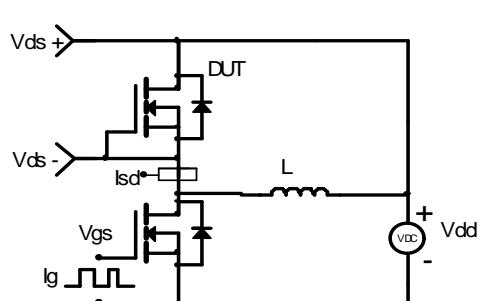
Resistive Switching Test Circuit & Waveforms



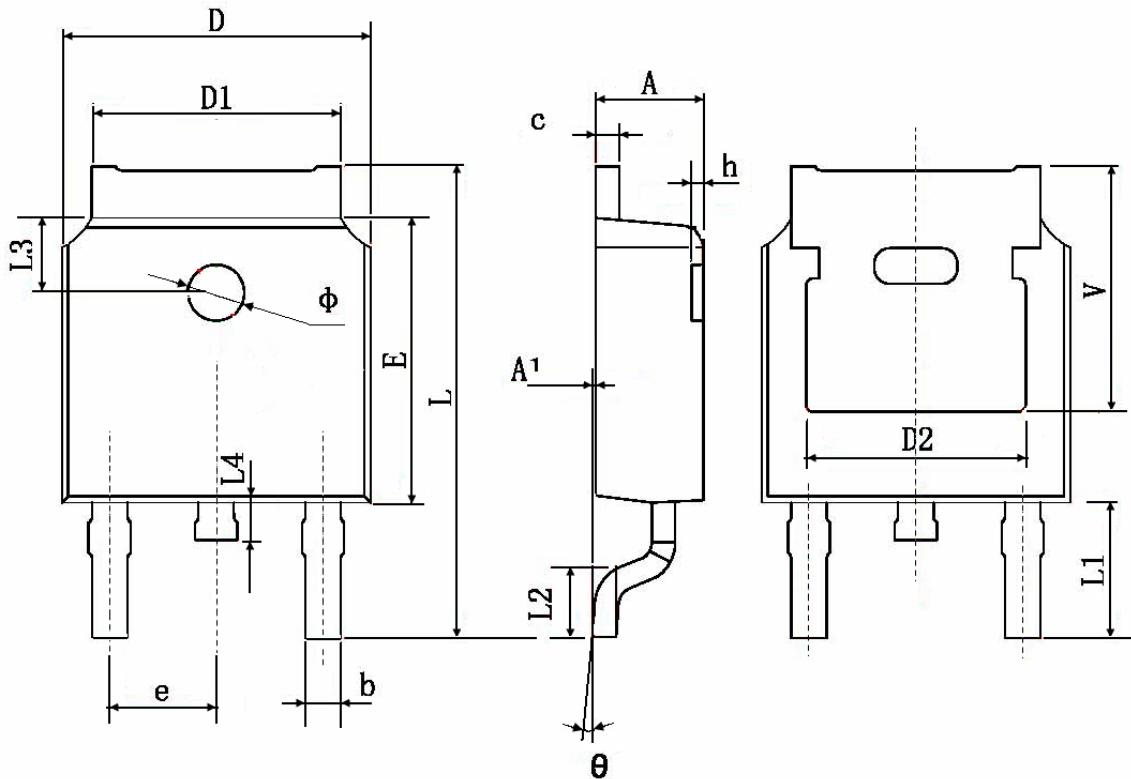
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

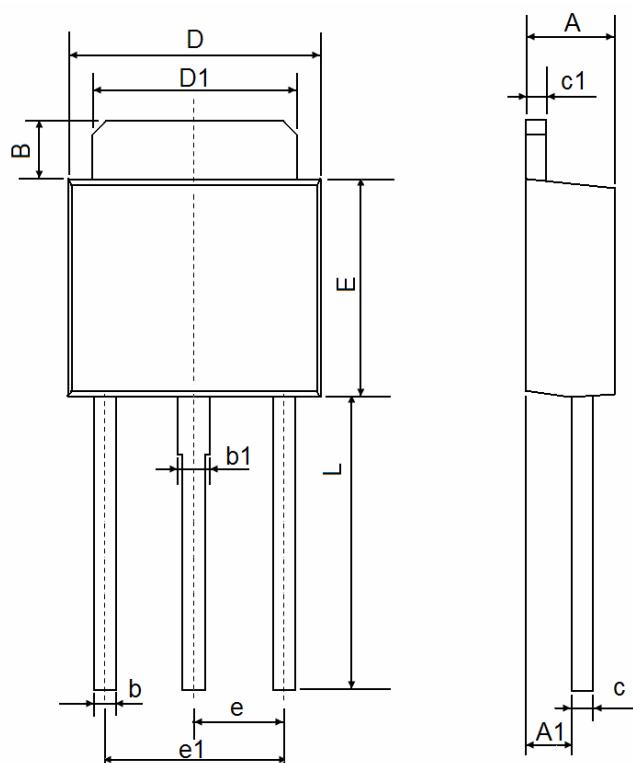


TO-252 Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.660	0.860	0.026	0.034
c	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	4.830 TYP.		0.190 TYP.	
E	6.000	6.200	0.236	0.244
e	2.186	2.386	0.086	0.094
L	9.800	10.400	0.386	0.409
L1	2.900 TYP.		0.114 TYP.	
L2	1.400	1.700	0.055	0.067
L3	1.600 TYP.		0.063 TYP.	
L4	0.600	1.000	0.024	0.039
Φ	1.100	1.300	0.043	0.051
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.350 TYP.		0.211 TYP.	

TO-251 Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A1	1.050	1.350	0.042	0.054
B	1.350	1.650	0.053	0.065
b	0.500	0.700	0.020	0.028
b1	0.700	0.900	0.028	0.035
c	0.430	0.580	0.017	0.023
c1	0.430	0.580	0.017	0.023
D	6.350	6.650	0.250	0.262
D1	5.200	5.400	0.205	0.213
E	5.400	5.700	0.213	0.224
e	2.300 TYP.		0.091 TYP.	
e1	4.500	4.700	0.177	0.185
L	7.500	7.900	0.295	0.311

Notes

1. All dimensions are in millimeters.
2. Tolerance $\pm 0.10\text{mm}$ (4 mil) unless otherwise specified
3. Package body sizes exclude mold flash and gate burrs. Mold flash at the non-lead sides should be less than 5 mils.
4. Dimension L is measured in gauge plane.
5. Controlling dimension is millimeter, converted inch dimensions are not necessarily exact.